

VDD OVER AND UNDERVOLTAGE MEASUREMENT TECHNIQUES USING MONITOR CELLS

ABSTRACT OF THE DISCLOSURE

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According to one embodiment, a method of testing an integrated circuit is provided. A reference voltage is coupled to each of a first and second comparator integrated on the chip. A supply voltage is compared to the reference voltage in a comparator to determine overvoltage or undervoltage conditions. The results of the

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comparison are stored and sizing and placing of at least one decoupling circuit in the circuit design is made based on the stored determinations.